Search	Notes
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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/690,779	TAKEUCHI ET AL.	
Examiner	Art Unit	
John S. Chu	1752	

SEARCHED			
Class	Subclass	Date	Examiner
430	138	12/2006	J2°
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
430	138	12/2000	ph
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
UPDATED	12/2006	J&C
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